## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination HAM, YONG-SUNG | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0124865	07-2003	Baek et al.	438/694
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	H	US-			
	1	US-	ï		
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				· · · · · · · · · · · · · · · · · · ·	
	Р			****		
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	TOTAL ATENIA DOCUMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.